

GENERAL DESCRIPTION

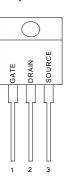
This high voltage MOSFET uses an advanced termination scheme to provide enhanced voltage-blocking capability without degrading performance over time. In addition, this advanced MOSFET is designed to withstand high energy in avalanche and commutation modes. The new energy efficient design also offers a drain-to-source diode with a fast recovery time. Designed for high voltage, high speed switching applications in power supplies, converters and PWM motor controls, these devices are particularly well suited for bridge circuits where diode speed and commutating safe operating areas are critical and offer additional and safety margin against unexpected voltage transients.

FEATURES

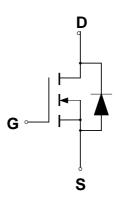
- Robust High Voltage Termination
- Avalanche Energy Specified
- Source-to-Drain Diode Recovery Time Comparable to a Discrete Fast Recovery Diode
- Diode is Characterized for Use in Bridge Circuits
- I_{DSS} and V_{DS}(on) Specified at Elevated Temperature

PIN CONFIGURATION

TO-220/TO-220FP Top View



SYMBOL



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS

Rating		Value	Unit
Drain to Current - Continuous		8.0	А
- Pulsed	I _{DM}	32	
Gate-to-Source Voltage - Continue		±20	V
- Non-repetitive	V _{GSM}	±40	V
Total Power Dissipation	PD		W
TO-220		125	
TO-220FP		40	
Operating and Storage Temperature Range	T _J , T _{STG}	-55 to 150	
Single Pulse Drain-to-Source Avalanche Energy - $T_J = 25$		320	mJ
$(V_{DD} = 100V, V_{GS} = 10V, I_L = 8A, L = 10mH, R_G = 25\Omega)$			
Thermal Resistance - Junction to Case		1.0	/W
- Junction to Ambient	θ _{JA}	62.5	
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 10 seconds	TL	260	



ORDERING INFORMATION

Part Number	Package	
CMT08N50N220	TO-220	
CMT08N50N220FP	TO-220 Full Package	

ELECTRICAL CHARACTERISTICS

Unless otherwise specified, $T_J = 25$.

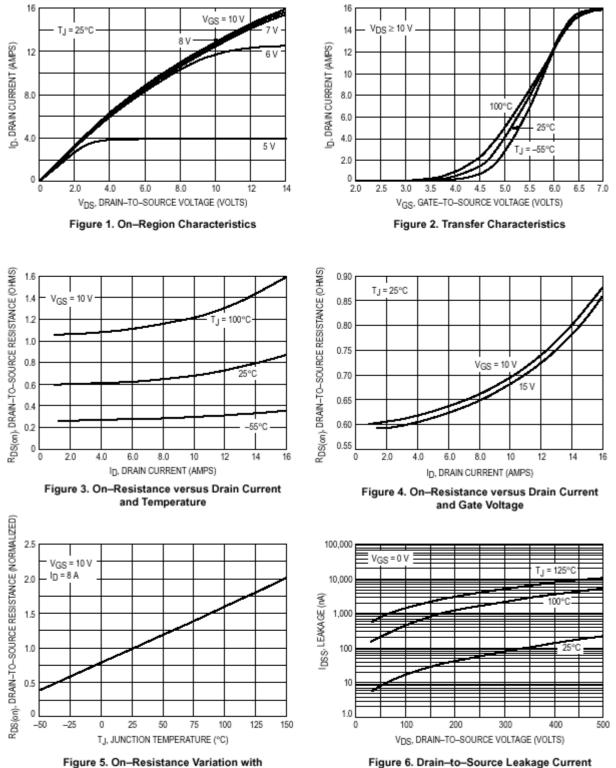
			CMT08N50			
Characteristic		Symbol	Min	Тур	Max	Units
Drain-Source Breakdown Voltage		V _{(BR)DSS}	500			V
$(V_{GS} = 0 V, I_{D} = 250 \mu A)$						
Drain-Source Leakage Current		I _{DSS}				μA
$(V_{DS} = 500 \text{ V}, V_{GS} = 0 \text{ V})$					25	
$(V_{DS} = 400 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125$)					250	
Gate-Source Leakage Current-Forward		I _{GSSF}			100	nA
$(V_{gsf} = 20 \text{ V}, V_{DS} = 0 \text{ V})$						
Gate-Source Leakage Current-Reverse	9	I _{GSSR}			100	nA
$(V_{gsr} = 20 \text{ V}, V_{DS} = 0 \text{ V})$						
Gate Threshold Voltage		$V_{GS(th)}$	2.0		4.0	V
$(V_{DS} = V_{GS}, I_D = 250 \ \mu A)$						
Static Drain-Source On-Resistance (Vo	_{ss} = 10 V, I _D = 4.0A) *	R _{DS(on)}			0.8	Ω
Drain-Source On-Voltage (V _{GS} = 10 V)		V _{DS(on)}		5.0	7.2	V
(I _D = 8.0 A)						
Forward Transconductance (V _{DS} = 50 \	/, I _D = 4.0A) *	g _{FS}	4.9			mmhos
Input Capacitance	$(V_{DS} = 25 V. V_{GS} = 0 V.$	C _{iss}		1450	1680	pF
Output Capacitance	(55 5) 66 5)	C _{oss}		190	246	pF
Reverse Transfer Capacitance	f = 1.0 MHz)	Crss		45.4	144	pF
Turn-On Delay Time		t _{d(on)}		15	50	ns
Rise Time	$(D_{1}, C_{1}, C_{2}, C_{2},$	tr		33	72	ns
Turn-Off Delay Time	(R _{Go} + C17n = 9.1Ω) *	t _{d(off)}		40	150	ns
Fall Time		t _f		32	60	ns
Total Gate Charge	$(V_{DS} = 400 \text{ V}, I_D = 8.0 \text{ A},$	Qq		40	64	nC
Gate-Source Charge		Q _{gs}		8.0		nC
Gate-Drain Charge	V _{GS} = 10 V)*	Q _{gd}		17		nC
Internal Drain Inductance		L _D		4.5		nH
(Measured from the drain lead 0.25"	from package to center of die)					
Internal Drain Inductance		Ls		7.5		nH
(Measured from the source lead 0.25" from package to source bond pad)		-				
SOURCE-DRAIN DIODE CHARACTE		•	•		•	•
Forward On-Voltage(1)		V _{SD}			1.5	V
Forward Turn-On Time	$(I_{\rm S} = 8.0 \text{ A}, V_{\rm GS} = 0 \text{ V},$	t _{on}		**		ns
Reverse Recovery Time	$d_{IS}/d_t = 100A/\mu s)$	t _{rr}		320		ns

* Pulse Test: Pulse Width 300µs, Duty Cycle 2%

** Negligible, Dominated by circuit inductance



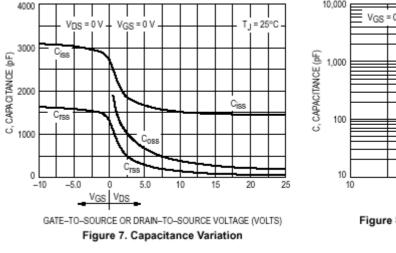
TYPICAL ELECTRICAL CHARACTERISTICS



versus Voltage

Temperature





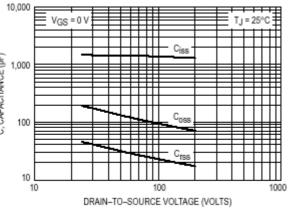
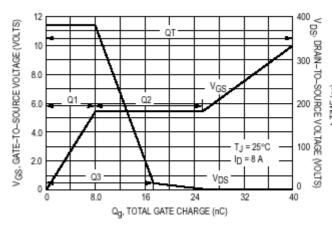
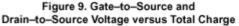
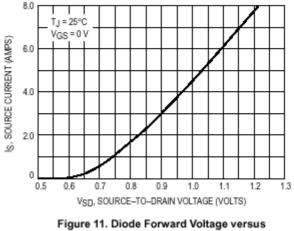


Figure 8. High Voltage Capacitance Variation







Current

1000 TJ = 25°C ID = 8 A VDD = 250 V VGS = 10 V (S) 100 td(off) 10 10 R_G- GATE RESISTANCE (OHMS)

Figure 10. Resistive Switching Time Variation versus Gate Resistance

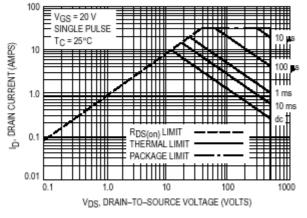


Figure 12. Maximum Rated Forward Biased Safe Operating Area



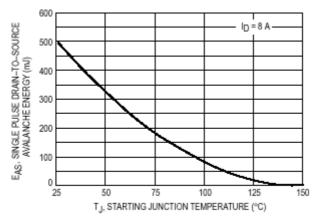


Figure 13. Maximum Avalanche Energy versus Starting Junction Temperature

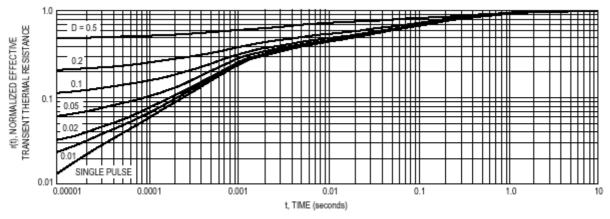
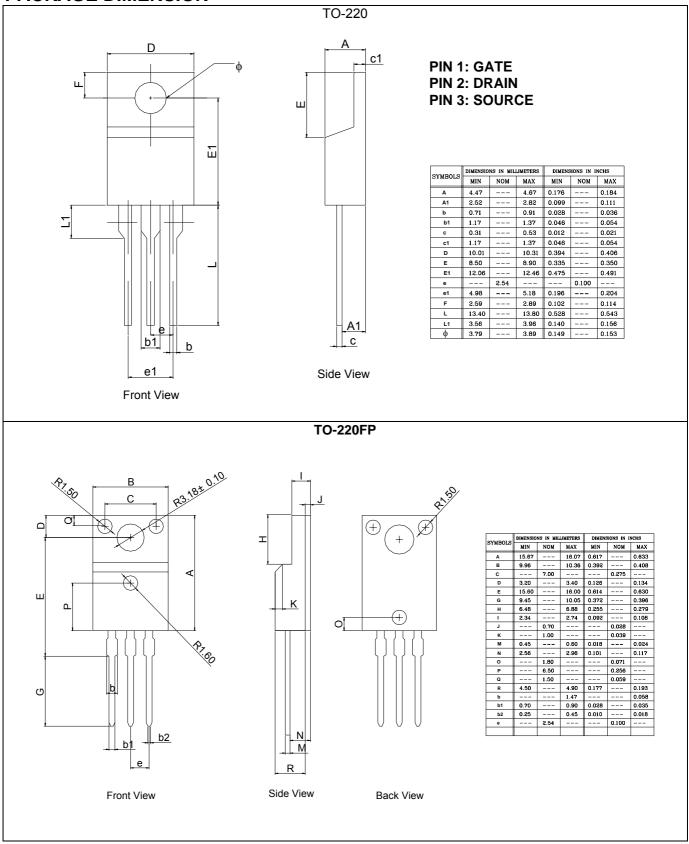


Figure 14. Thermal Response



PACKAGE DIMENSION





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